

## VARIABLE DELAY LINE

### Technical Field of the Invention

5        The present invention relates generally to delay elements, and in particular, the  
present invention relates to variable delay lines used in delay lock loops.

### Background of the Invention

Electronic systems typically include circuit boards, and the circuit boards  
10      typically include semiconductor devices. Some semiconductor devices communicate  
with each other using clock signals for timing. For example, devices using a common  
clock signal can communicate with one another by driving data when sending, and  
latching data when receiving, using timing derived from the common clock signal.

Clock signals can be used to control timing internal to the semiconductor  
15      devices, and can also be used to control timing external to the semiconductor devices.  
For example, in devices having internal storage elements, or "synchronous" elements,  
an internal clock signal is "fanned out" to the synchronous elements internal to the  
device such that the internal synchronous elements can reliably communicate. These  
semiconductor devices can also drive data from within the device through conductors at  
20      the device boundary, and drive signal nodes external to the device.

When a clock signal is received by a semiconductor device, it undergoes a finite  
amount of delay when entering the device. This delay can be caused by trace  
impedance, input driver delay, or the like. The clock signal on the semiconductor die is,  
therefore, delayed with respect to the clock outside the device. When one clock signal  
25      has undergone a delay different from another clock signal, the two clock signals are said  
to have a phase offset. When the clock signal internal to the device has a phase offset  
relative to a clock signal outside the device, timing from one device to another can be  
upset, thereby causing errors when the devices are communicating.

Delay lock loops have been devised to add additional clock delay to the clock  
30      signal such that the total delay is substantially equal to an integer number of clock

periods. If the total delay is an integer number of clock periods, the phase offset is zero. When a device is powered on, or when the device is reset, the delay lock loop begins to operate. Delay lock loops typically add or subtract a unit delay element from the internal clock path each clock period until a desired phase offset between the internal and external clock signals is reached. This can be time consuming, especially if the initial phase offset is large, or if the clock frequency is low.

5 For the reasons stated above, and for other reasons stated below which will become apparent to those skilled in the art upon reading and understanding the present specification, there is a need in the art for alternate methods and apparatus for

10 controlling phase offsets between clock signals.

#### Summary of the Invention

The above mentioned problems and other problems are addressed by the present invention and will be understood by reading and studying the following specification.

15 In one embodiment, a method of setting a delay value in a delay lock loop includes delaying a first signal in a variable delay line to generate a second signal, and comparing a phase of the first signal with a phase of the second signal to generate a first control signal. The method further includes delaying the first signal by a first substantially fixed amount to generate a third signal, and comparing the phase of the

20 second signal with a phase of the third signal to generate a second control signal. Responsive to the first control signal the variable delay line is adjusted by a first delay amount, and responsive to the second control signal the variable delay line is adjusted by a second delay amount.

In another embodiment, an integrated circuit includes a variable delay line

25 having an input node, an output node, a fine adjustment node, and a coarse adjustment node. The integrated circuit further includes a phase detector configured to compare a signal on the input node with a signal on the output node and drive signals onto the fine adjustment node and the coarse adjustment node.

Brief Description of the Drawings

Figure 1 is an integrated circuit that includes a delay lock loop of the present invention.

5           Figure 2 is a phase detector of the present invention.

Figure 3 is a variable delay line of the present invention.

Figure 4 is a shift register having coarse and fine control in accordance with the present invention.

10          Figure 5 is an alternate embodiment of a variable delay line of the present invention.

Figure 6 shows waveforms during the operation of a variable delay line.

15          Figure 7 shows a processing system according to the invention.

Detailed Description of the Invention

In the following detailed description of the invention, reference is made to the accompanying drawings which form a part hereof, and in which is shown, by way of illustration, specific embodiments in which the invention may be practiced. In the drawings, like numerals describe substantially similar components throughout the several views. These embodiments are described in sufficient detail to enable those skilled in the art to practice the invention. Other embodiments may be utilized and structural, logical, and electrical changes may be made without departing from the scope of the present invention. The following detailed description is, therefore, not to be taken in a limiting sense, and the scope of the present invention is defined only by the appended claims, along with the full scope of equivalents to which such claims are entitled.

25          Figure 1 shows an integrated circuit having a delay lock loop. Integrated circuit 100 includes input buffer 106, device element 112, and a delay lock loop. The delay lock loop includes variable delay line 108, phase detector 130, device element delay model 116, and delay element 120.

Integrated circuit 100 receives an external clock into input buffer 106 on input node 102. Input buffer 106 is at the device boundary, and inserts a "device boundary

30          30

Client Ref. No. 99-0748

delay" in the signal on input node 102. A device boundary delay can be introduced by mechanisms other than input buffer 106. For example, a delay line can insert a device boundary delay. Input buffer 106 receives the external clock signal into integrated circuit 100, and provides a delayed version of the external clock to variable delay line 108 and phase detector 130 on node 104. For the purpose of description, the clock signal on node 104 is referred to herein as "E\_CLOCK." E\_CLOCK is delayed from the external clock on node 102, by an amount equal to the device boundary delay introduced by input buffer 106.

5 Variable delay line 108 receives E\_CLOCK on node 104, and subjects

10 E\_CLOCK to further delay to generate the internal clock on node 110. The internal clock on node 110 is used internal to integrated circuit 100. In some embodiments, such as the embodiment shown in Figure 1, the internal clock is fanned out to device elements within the integrated circuit. Device element 112 is representative of many possible device elements within integrated circuit 100, and can be any type of circuit

15 element that uses the internal clock. Examples include, but are not limited to, flip-flops, latches, output registers, and output buffers. Device element 112 receives the internal clock on control input node 114. Control input node 114 can be a clock input, an output enable input, a data input, or the like. For example, in some embodiments, device element 112 is a flip-flop and control input node 114 is a clock input. In other

20 embodiments, device element 112 is a buffer and control input node 114 is an output enable that switches an output from a high impedance state to a driven state.

The internal clock on node 110 is also fed back through device element delay model 116 and delay element 120 to phase detector 130. Device element delay model 116 has a delay characteristic that closely matches that of device element 112, and delay element 120 has a delay characteristic that closely matches that of input buffer 106. The delayed clock signal on node 122 is referred to herein as "I\_CLOCK."

25 Phase detector 130 compares the phase of I\_CLOCK to the phase of E\_CLOCK and controls the delay of variable delay line 108. In the embodiment of Figure 1, phase detector 130 generates a fine adjustment control on node 132 and a coarse adjustment control on node 134. When the phase offset between E\_CLOCK and I\_CLOCK is

large, the coarse adjustment control can make large adjustments to the delay of variable delay line 108, and when the phase offset is small, the fine adjustment control can make smaller adjustments. Node 132 and node 134 can include multiple signal lines. For example, node 132 may include more than one signal line, and node 134 may include 5 more than one signal line. The operation of phase detector 130 and variable delay line 108 is described in greater detail with reference to the remaining figures.

In some embodiments, when variable delay line 108 is in steady state, the sum of the delay in variable delay line 108, device element delay model 116, and delay element 120 is an integer number of clock periods. When the sum of the delay is an 10 integer number of clock periods, E\_CLOCK and I\_CLOCK substantially align in phase, and phase detector 130 does not make adjustments.

In the embodiment shown in Figure 1, when E\_CLOCK and I\_CLOCK are substantially aligned in phase, the internal clock on node 110 leads the external clock on node 102 by a delay substantially equal to that of device element delay model 116. This 15 can be useful when, for example, device element 112 drives data signals or control signals off integrated circuit 100. In embodiments where device element 112 is an output register and control input node 114 is a clock input, device element delay model 116 can model the clock-to-output delay of the output register. Device element delay model 116 can also exhibit a delay that is more or less than the clock-to-output delay of 20 the output register. This can be useful for generating specific timing relationships between the external clock and the signal driven external to integrated circuit 100.

In some embodiments, device element delay model 116 is omitted. In some of these embodiments, device element 112 is a synchronous device such as a flip-flop that drives data internal to integrated circuit 100. In other embodiments, integrated circuit 25 100 includes multiple delay lock loops for supplying clock signals to different portions of integrated circuit 100. For example, multiple device elements 112 of different types can exist within integrated circuit 100. When different device elements 112 exhibit different delays, multiple delay lock loops can be utilized to supply internal clock signals with desired phase relationships.

Integrated circuit 100 can be any type of integrated circuit capable of utilizing a delay lock loop. In some embodiments, integrated circuit 100 is a memory device. In some of these embodiments, delay element 112 is a synchronous output element. In others of these embodiments delay element 112 is an asynchronous output element. In other embodiments, integrated circuit 100 is an application-specific integrated circuit (ASIC). In still other embodiments, integrated circuit 100 is a processor, such as a microprocessor, digital signal processor, or the like.

The embodiment shown in Figure 1 provides a mechanism that adjusts a variable delay quickly. Coarse adjustments can be made when phase offsets are large, and fine adjustments can be made when phase offsets are large. When integrated circuit 100 can benefit from a delay lock loop that locks quickly, in part because a substantially fixed relationship between multiple clock signals can be achieved quickly.

Figure 2 shows phase detector 130. Phase detector 130 includes phase comparators 220, 230, and 240. Phase detector 130 also includes delay element 206 and delay element 208. Phase detector 130 receives E\_CLOCK on node 202 and I\_CLOCK on node 204. Phase comparator 220 generates a fine increase signal on node 222, and a fine decrease signal on node 224. Phase comparator 230 generates a coarse increase signal on node 232, and phase comparator 240 generates a coarse decrease signal on node 242.

Phase comparator 240 compares I\_CLOCK on node 204 with a delayed E\_CLOCK on node 212. When the phase of I\_CLOCK lags the phase of the delayed E\_CLOCK, the coarse decrease signal is asserted on node 242. Stated differently, when the phase of I\_CLOCK lags the phase of E\_CLOCK by an amount greater than the delay of delay element 208, phase comparator 240 asserts the coarse decrease signal on node 242. Phase comparator 230 operates in a manner similar to phase comparator 240, with the exception that I\_CLOCK is delayed rather than E\_CLOCK. When the phase of the delayed I\_CLOCK on node 210 lags the phase of E\_CLOCK, phase comparator 230 asserts the coarse increase signal on node 232. Stated differently, when the phase of I\_CLOCK lags the phase of E\_CLOCK by an amount greater than the delay of delay element 206, phase comparator 230 asserts the coarse increase signal on node 232.

In the embodiment shown in Figure 2, the coarse increase signal on node 232 and the coarse decrease signal on node 242 can be used to make coarse adjustments in a variable delay line, such as variable delay line 108 (Figure 1). In some embodiments, delay elements 206 and 208 have delay values substantially equal to the coarse delay increments controlled by the coarse increase signal and the coarse decrease signal. For example, when phase comparators 230 and 240 are used for coarse adjustment of a variable delay line such as variable delay line 108, the variable delay line can increase the delay by an amount substantially equal to the delay of delay element 206 when the coarse increase signal is asserted. As a result, I\_CLOCK is retarded relative to E\_CLOCK by an amount substantially equal to the delay of delay element 206.

10 Likewise, the coarse decrease signal can cause a decrease in delay substantially equal to the delay of delay element 208. As a result, I\_CLOCK is advanced with respect to E\_CLOCK by an amount substantially equal to the delay of delay element 208.

If I\_CLOCK lags E\_CLOCK less than the delay of delay element 206, the coarse increase signal on node 232 is not asserted. Likewise, if E\_CLOCK lags I\_CLOCK less than the delay of delay element 208, coarse decrease signal on node 242 is not asserted. Delay element 206 and 208 determine a phase offset window, such that when the phase offset between E\_CLOCK and I\_CLOCK is within the phase offset window, the coarse adjustment control signals are not asserted.

15 20 Phase comparator 220 compares E\_CLOCK and I\_CLOCK directly. When I\_CLOCK lags E\_CLOCK more than a fine threshold, the fine increase signal on node 222 is asserted. Likewise, when I\_CLOCK lags E\_CLOCK more than a fine threshold, the fine decrease signal on node 224 is asserted. The fine increase signal on node 222 and the fine decrease signal on node 224 can be used as fine adjustment control signals on a variable delay line such as variable delay line 108 (Figure 1). When the fine increase signal on node 222 is asserted, the delay of variable delay line 108 is increased, which causes I\_CLOCK on node 204 to retard slightly. In contrast, when the fine decrease signal on node 224 is asserted, the variable delay of variable delay line 108 is decreased, which causes I\_CLOCK on node 204 to advance slightly.

The embodiment shown in Figure 2 includes three phase comparators. In some embodiments, more than three phase comparators are used. For example, multiple coarse increase signals can be generated using multiple phase comparators, each being coupled to a different delay element corresponding to delay element 206. Also, 5 multiple coarse decrease signals can be generated using multiple phase comparators, each being coupled to a different delay element corresponding to delay element 208. In these embodiments, greater control of a variable delay line can be exercised.

Comparators 230 and 240 in the embodiment shown in Figure 2 compare the phase of two signals after a delay has been introduced. In other embodiments, phase 10 comparators compare the phase of two signals directly and produce a signal having a phase offset value. The phase offset value is then compared to phase offset thresholds to generate coarse and fine adjustment control signals. For example, the phase offset value can be compared to a fine threshold and a coarse threshold. When the phase offset value is larger than the coarse threshold, one of the coarse adjustment control 15 signals can be asserted. When the phase offset value is larger than the fine threshold, but not larger than the coarse threshold, one of the fine adjustment control signals can be asserted, and when the phase offset value is less than the fine threshold, the adjustment control signals can remain de-asserted.

Figure 3 shows variable delay line 108A. Variable delay line 108A is one 20 embodiment of variable delay line 108 (Figure 1). Variable delay line 108A includes multiple delay cells shown in Figure 3 as delay cells 304, 308, 312, and 316. Four delay cells are shown in variable delay line 108A; however, any number of delay cells can be utilized without departing from the scope of the present invention.

Variable delay line 108A also includes shift register 330. Shift register 330 has, 25 as control inputs, a fine increase signal on node 332, a fine decrease signal on node 334, a coarse increase signal on node 336, and a coarse decrease signal on node 338. These control inputs correspond to the fine adjustment controls and coarse adjustment controls as shown in Figure 2.

Shift register 330 includes multiple storage elements such as flip-flops, latches, 30 or the like, each having a control signal output. Each storage element within shift

register 330 holds a single bit in the shift register, and the state of the bit is reflected on the control signal output. The control signal outputs from shift register 330 include control signals on nodes 320, 322, 324, and 326. When a control signal output is asserted, the corresponding delay cell routes the non-E\_CLOCK input to the output.

5 For example, when the control signal on node 326 is not asserted, delay cell 316 routes E\_CLOCK to node 318. This corresponds to the shortest delay in variable delay line 108A. In contrast, when the control signal on node 326 is asserted, delay cell 316 routes the signal from node 314 to node 318. In this case, the delay of at least delay cell 312 is added to the delay of delay cell 316.

10 Variable delay line 108A achieves variable delay by routing E\_CLOCK through a variable number of delay cells, each having a "unit" delay, to produce the internal clock on node 318. The shortest delay is achieved by routing E\_CLOCK through only delay cell 316. Increasing amounts of delay are achieved by adding additional delay cells to delay cell 316. For example, when delay element 312 is cascaded with delay cell 316, the delay in variable delay line 108A is increased. Additional delay cells are added when shift register 330 is "shifted left." When shift register 330 is shifted left, additional control signal outputs are asserted, and additional delay is added to variable delay line 108A.

15 In some embodiments, shift register 330 can be shifted by more than one storage element to create a coarse increment in the delay of variable delay line 108A. In the embodiment of Figure 3, the coarse increase signal causes a shift left of more than one storage element, and the coarse decrease signal causes a shift right of more than one storage element within shift register 330. In other embodiments, multiple coarse increase and coarse decrease signals are used, each causing shifts of different amounts. 20 The fine increase signal and fine decrease signal cause shifts smaller than the shifts caused by the coarse adjustment signals. In some embodiments, the fine adjustment signals cause shifts of one storage element at a time.

25 Figure 4 shows shift register 330. Shift register 330 includes storage elements arranged in blocks 410 and 440. Block 410 includes four storage elements corresponding to output nodes 412, 414, 416, and 418. Likewise block 440 includes

four storage elements corresponding to output nodes 442, 444, 446, and 448. Block 410 receives a fine increase signal from node 470 on shift left input node 424, and block 440 receives the fine increase signal on shift left input node 454. Block 410 receives a fine decrease signal from node 472 on shift right input node 426, and block 440 receives the fine decrease signal on shift right input node 456. When the fine increase signal is asserted, blocks 410 and 440 perform a shift left operation. Likewise, when the fine decrease signal is asserted, blocks 410 and 440 perform a shift right operation.

The shift left and shift right operations perform a shift of a single bit. For example, if the storage elements corresponding to output nodes 412 and 414 are set, and the remaining storage elements are not set, after a shift left operation storage elements corresponding to output node 412, 414, and 416 are set. When shift register 330 is utilized in a variable delay line such as variable delay line 108A (Figure 3), this corresponds to a single delay cell, such as delay cell 312, being inserted in the delay path.

The shift left and shift right operations work across block boundaries. For example, if the storage element corresponding to output node 418 is set, and the storage element corresponding to output node 442 is not set, a shift left operation will set the storage element corresponding to output node 442. The state of output node 418 is input to block 440 at least significant bit input 419. When block 440 performs a left shift operation, the storage element corresponding to output node 442 receives the value at the least significant bit input 419. Shift right operations work the same way as shift left operations, with the exception that they work to the right rather than the left.

The coarse increase signal on node 474 is input to logic gates 420 and 450. Logic gate 420 combines the coarse increase signal with a most significant bit from a less significant stage on node 421. The output of logic gate 420 drives the "set all" input node 422 of block 410. The set all input node, when asserted, causes all storage elements within block 410 to be set. Likewise, logic gate 450 combines the coarse increase signal with the most significant bit from block 410 and drives the set all input node 452 of block 440. When the most significant bit of block 410 is asserted, output node 418 is also asserted. If, when output node 418 is asserted, the coarse increase

signal is also asserted, set all input node 452 of block 440 is also asserted. As a result, all storage elements within block 440 are set in one operation.

The coarse decrease signal on node 476 causes an operation similar to the coarse increase signal, but in the opposite direction. Coarse decrease signal on node 476 is

5      input to logic gates 458 and 428. Logic gates 458 and 428 also receive the least significant bit of the more significant stage. If the coarse decrease signal is asserted when the least significant bit of the more significant stage is not set, the "reset all" input node is asserted causing the entire block of storage elements to be reset. For example, block 410 receives a signal from logic gate 428 on reset all input node 430. When the

10     least significant bit of block 440 is not set, output node 442 is not asserted. If, when output 442 is not asserted, the coarse decrease signal on node 476 is asserted, reset all input node 430 will be asserted. This causes all storage elements within block 410 to be reset.

In the embodiment of Figure 4, a shift register can be shifted left or right by a single storage element, or can be shifted left or right by four storage elements at a time. In other embodiments, blocks hold more than four storage elements, resulting in larger coarse adjustments. In other embodiments, blocks hold less than four storage elements, resulting in smaller coarse adjustments. In still other embodiments, blocks hold varying numbers of storage elements, such that different size coarse adjustments can be made.

20     Figure 5 is an alternate embodiment of a variable delay line. Variable delay line 108B is one embodiment of variable delay line 108. Variable delay line 108B is divided into a coarse adjustment portion, and a fine adjustment portion. The coarse adjustment portion includes shift register 502 and coarse delay cells 532, 534, and 536. The fine adjustment portion includes shift register 512 and fine delay cells 542, 544, and 546. The coarse adjustment portion and the fine adjustment portion each function similar to variable delay line 108A (Figure 3). For example, shift register 502 receives the coarse increase signal from node 508 on shift left input node 504. Shift register 502 also receives the coarse decrease signal from node 510 on shift right input node 506. When shift register 502 receives an asserted signal on shift left input node 504, more

25     30    output nodes become asserted. When shift register 502 receives an asserted signal on

the shift right input node 506, fewer output nodes are asserted. The result is a change in the number of coarse delay cells included within the clock path of variable delay line 108B.

The coarse delay cells receive E\_CLOCK from node 530 and produce an intermediate clock on node 540. The intermediate clock on node 540 is received by the fine adjustment portion of variable delay line 108B. Node 540 is input to fine delay cells 542, 544, and 546. Shift register 512, in response to signals received on shift left input node 514 and shift right input node 516, increases or decreases the number of output nodes asserted. This is similar to the operation of shift register 502. After 10 E\_CLOCK travels through coarse delay cells and fine delay cells, an internal clock is generated on node 560.

Variable delay line 108B is shown with three coarse delay cells, and three fine delay cells. Any number of coarse delay cells and fine delay cells can be used without departing from the scope of the present invention.

Figure 6 shows waveforms of signals during the operation of a variable delay line. One variable delay line embodiment, the operation of which is described by Figure 6, includes phase detector 130 (Figure 2), variable delay line 108A (Figure 3), and shift register 330 (Figure 4). E\_CLOCK 602 corresponds to E\_CLOCK on node 202, and I\_CLOCK 622 corresponds to I\_CLOCK on node 204 (Figure 2). The phase of 15 E\_CLOCK 602 is compared to the phase of I\_CLOCK 622 during each period of E\_CLOCK 602. For example, during period 680, E\_CLOCK 602 is compared to I\_CLOCK 622 and phase difference 604 results. Phase difference 604 is a phase 20 difference in which E\_CLOCK 602 lags I\_CLOCK 622 by more than the delay of delay line 206 (Figure 2). As a result, coarse increase signal 640 is asserted at 642. Fine increase signal 650 is also asserted at 652.

As a result of the assertions of coarse increase signal 640 and fine increase signal 650, I\_CLOCK 622 is slightly retarded relative to E\_CLOCK 602. When the comparison occurs again during period 682, phase difference 606 results. Phase difference 606 is still greater than the delay of delay line 206, and as a result, coarse 25 increase signal 640 is asserted at 644, and fine increase signal 650 is asserted at 654.

30

I\_CLOCK 622 is again delayed further as a result. During period 684 the comparison of E\_CLOCK 602 and I\_CLOCK 622 yields phase difference 608. Phase difference 608 is less than the delay of delay line 206, and as a result, coarse increase signal 640 is not asserted, but fine increase signal 650 is asserted at 656. During period 686 the 5 phase comparison yields phase difference 610, which results in fine increase signal 650 being asserted at 658. Thereafter, the phase comparison yields phase offset 612 which is less than a threshold in phase comparator 220, and neither coarse increase signal 640 nor fine increase signal 650 are asserted.

In the operational scenario shown in Figure 6, E\_CLOCK 602 lags I\_CLOCK 10 622, and the delay of the variable delay line is increased until the phase of E\_CLOCK 602 and I\_CLOCK 622 substantially align. Coarse decrease signal 660 and fine decrease signal 670 were not used in this scenario because I\_CLOCK 622 did not lag E\_CLOCK 602. One skilled in the art will understand that when I\_CLOCK 622 lags E\_CLOCK 602, coarse decrease signal 660 and fine decrease signal 670 can be used to 15 reduce phase offsets until E\_CLOCK 602 and I\_CLOCK 622 substantially align in phase.

Figure 7 shows a processing system according to the invention. System 700 includes processor 702, and memory 704. System 700 can also include many other devices such as memory controllers, input/output devices, and others. These other 20 devices are omitted from Figure 7 to accentuate the items remaining in the figure. Processor 702 can be a microprocessor, digital signal processor, embedded processor, microcontroller, or the like. Memory 704 is a memory device that includes a delay lock loop such as the delay lock loop shown in Figure 1. Processor 702 and memory 704 communicate using address signals on node 708, control signals on node 710, and data 25 signals on node 706. In some embodiments, a clock signal generated by a delay lock loop internal to memory 704 is used to drive control inputs of circuit elements that drive outputs of memory 704. For example, data signals on node 706 can be driven by circuit elements such as device element 112 (Figure 1). The delay lock loop internal to memory 704 provides a mechanism for efficient communications between processor 30 702 and memory 704.

### Conclusion

A variable delay line and method therefor have been described. The variable delay line can be used in a delay lock loop within an integrated circuit. The variable delay line receives coarse and fine adjustment controls from phase comparators. The 5 coarse and fine adjustment controls cause a shift register associated with the delay element to shift varying amounts, thereby causing a varying amount of delay to be added or removed from the variable delay line. In one embodiment, the shift register is grouped into blocks, and the shift register shifts a block at a time in response to the coarse controls. In another embodiment, one shift register adds or removes coarse delay 10 cells in response to the coarse controls, and another shift register adds or removes fine delay cells in response to the fine controls.

Although specific embodiments have been illustrated and described herein, it will be appreciated by those of ordinary skill in the art that any arrangement which is calculated to achieve the same purpose may be substituted for the specific embodiment 15 shown. This application is intended to cover any adaptations or variations of the present invention. Therefore, it is manifestly intended that this invention be limited only by the claims and the equivalents thereof.